

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HILLIGER ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0039837	04-2002	Tohda et al.	438/689
	B	US-2003/0139017	07-2003	Park, Jong-Bum	438/396
	C	US-2003/0017669	01-2003	Kiyotoshi et al.	438/245
	D	US-2003/0087520	05-2003	Chen et al.	438/643
	E	US-2002/0117399	08-2002	Chen et al.	205/125
	F	US-2002/0098682	07-2002	Kim et al.	438/627
	G	US-2003/0098466	05-2003	Morozumi, Yukio	257/200
	H	US-2004/0102035	05-2004	Lee, Jong-Hyun	438/637
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1 233449	08-2002	European	Vanhaelemeersch et al	
	O	JP 9-063989	03-1997	Japan	KITAHATA	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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